BUK9Y27-40B

N-channel TrenchMOS logic level FET

Rev. 04 — 7 April 2010

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Q101 compliant

- Suitable for logic level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

1.3 Applications

- 12 V loads
- Automotive systems

- General purpose power switching
- Motors, lamps and solenoids

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	40	V
I _D	drain current	$V_{GS} = 5 \text{ V; } T_{mb} = 25 \text{ °C;}$ see <u>Figure 1</u> ; see <u>Figure 4</u>	-	-	34	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	59.4	W
Static char	racteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 5 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 12}{\text{Figure } 13};$ see Figure 13	-	22	27	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _i = 25 °C; see <u>Figure 12</u>	-	18	24	mΩ



Table 1. Quick reference data ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanche i	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$I_D = 34$ A; $V_{sup} \le 40$ V; $R_{GS} = 50$ Ω ; $V_{GS} = 5$ V; $T_{j(init)} = 25$ °C; unclamped	-	-	39	mJ
Dynamic characteristics						
Q_{GD}	gate-drain charge	$V_{GS} = 5 \text{ V}; I_D = 15 \text{ A};$ $V_{DS} = 32 \text{ V}; \text{ see } \frac{\text{Figure } 14}{\text{ Figure } 14}$	-	4.2	-	nC

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	D
3	S	source		
4	G	gate		
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK9Y27-40B	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

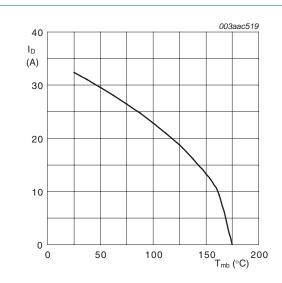
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	40	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	-	40	V
V_{GS}	gate-source voltage			-15	-	15	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 5 V; see <u>Figure 1</u> ; see <u>Figure 4</u>		-	-	34	А
		$T_{mb} = 100 ^{\circ}\text{C}; V_{GS} = 5 \text{V}; \text{see} \frac{\text{Figure 1}}{}$		-	-	24	Α
I _{DM}	peak drain current	T_{mb} = 25 °C; $t_p \le 10 \mu s$; pulsed; see Figure 4		-	-	136	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	59.4	W
T _{stg}	storage temperature			-55	-	175	°C
T _j	junction temperature			-55	-	175	°C
Source-drain	diode						
I _S	source current	T _{mb} = 25 °C		-	-	34	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	-	136	Α
Avalanche ru	ıggedness						
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 34 A; $V_{sup} \le$ 40 V; R_{GS} = 50 Ω ; V_{GS} = 5 V; $T_{j(init)}$ = 25 °C; unclamped		-	-	39	mJ
E _{DS(AL)R}	repetitive drain-source avalanche energy	see <u>Figure 3</u>	[1][2][3] [4]	-	-	-	J

^[1] Maximum value not quoted. Repetitive rating defined in avalanche rating figure.

^[2] Single-pulse avalanche rating limited by maximum junction temperature of 175 $^{\circ}$ C.

^[3] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

^[4] Refer to application note AN10273 for further information.



 $P_{\text{der}} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \%$

Fig 1. Continuous drain current as a function of mounting base temperature

Fig 2. Normalized total power dissipation as a function of mounting base temperature

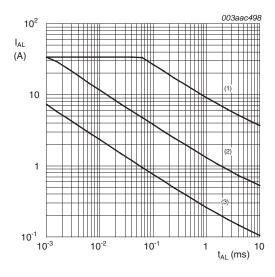
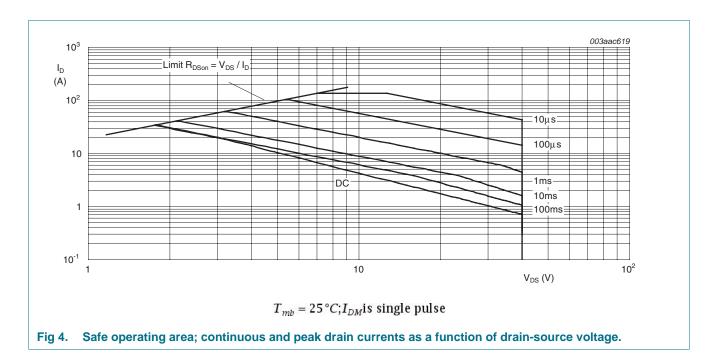


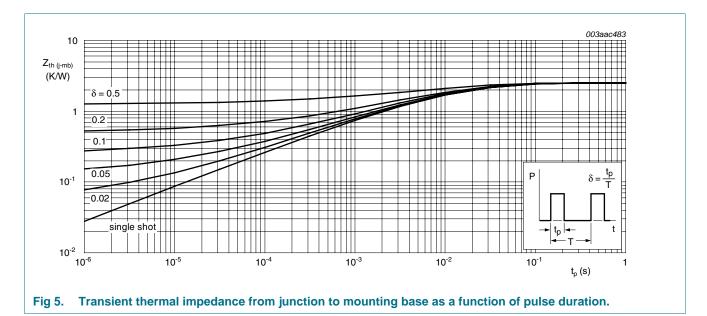
Fig 3. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time



5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 5	-	-	2.53	K/W



6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	36	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	40	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	1.1	1.5	2	V
	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 175$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	0.5	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	-	-	2.3	V
I _{DSS}	drain leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μΑ
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
I _{GSS}	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 15 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
		$V_{DS} = 0 \text{ V}; V_{GS} = -15 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
R _{DSon}	drain-source on-state resistance	$V_{GS} = 5 \text{ V}$; $I_D = 15 \text{ A}$; $T_j = 25 \text{ °C}$; see Figure 12; see Figure 13	-	22	27	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	-	30	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 15 \text{ A}; T_j = 175 °C;$ see Figure 13	-	-	57	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C};$ see Figure 12	-	18	24	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 15 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 5 \text{ V};$	-	11	-	nC
^						
U GS	gate-source charge	see Figure 14	-	2.5	-	nC
	gate-source charge gate-drain charge	see <u>Figure 14</u>	-	2.5 4.2	-	
Q_{GD}		V _{GS} = 0 V; V _{DS} = 25 V; f = 1 MHz;				nC
Q _{GD} C _{iss}	gate-drain charge		-	4.2	-	nC nC
Q _{GD} C _{iss} C _{oss}	gate-drain charge input capacitance	V _{GS} = 0 V; V _{DS} = 25 V; f = 1 MHz;	-	4.2 719	- 959	nC nC pF
Q _{GD} C _{iss} C _{oss} C _{rss}	gate-drain charge input capacitance output capacitance reverse transfer	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 15}}{\text{Figure 20}}$ $V_{DS} = 30 \text{ V}; R_L = 2 \Omega; V_{GS} = 5 \text{ V};$		4.2 719 146	- 959 175	nC nC pF
Q_{GD} C_{iss} C_{oss} C_{rss}	gate-drain charge input capacitance output capacitance reverse transfer capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 15}}{\text{ or } 15 \text{ or } 15 \text$	- - -	4.2 719 146 83	- 959 175 114	nC nC pF pF
Q_{GD} C_{iss} C_{oss} C_{rss} $t_{d(on)}$	gate-drain charge input capacitance output capacitance reverse transfer capacitance turn-on delay time	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 15}}{\text{Figure 20}}$ $V_{DS} = 30 \text{ V}; R_L = 2 \Omega; V_{GS} = 5 \text{ V};$	- - - -	4.2 719 146 83 14.5	- 959 175 114	nC nC pF pF pF
Q _{GD} C _{iss} C _{oss} C _{rss} t _{d(on)} t _r	gate-drain charge input capacitance output capacitance reverse transfer capacitance turn-on delay time rise time	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 15}}{\text{Figure 20}}$ $V_{DS} = 30 \text{ V}; R_L = 2 \Omega; V_{GS} = 5 \text{ V};$	- - - -	4.2 719 146 83 14.5 35	- 959 175 114 -	nC nC pF pF pF
QGD Ciss Coss Crss td(on) tr td(off)	gate-drain charge input capacitance output capacitance reverse transfer capacitance turn-on delay time rise time turn-off delay time	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 15}}{\text{Figure 20}}$ $V_{DS} = 30 \text{ V}; R_L = 2 \Omega; V_{GS} = 5 \text{ V};$	- - - -	4.2 719 146 83 14.5 35 40	- 959 175 114 -	nC nC pF pF pF
Q _{GD} C _{iss} C _{oss} C _{rss} t _{d(on)} t _r t _{d(off)}	gate-drain charge input capacitance output capacitance reverse transfer capacitance turn-on delay time rise time turn-off delay time fall time	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 15}}{\text{Figure 20}}$ $V_{DS} = 30 \text{ V}; R_L = 2 \Omega; V_{GS} = 5 \text{ V};$	- - - -	4.2 719 146 83 14.5 35 40	- 959 175 114 -	nC nC pF pF pF
$\begin{array}{l} Q_{GS} \\ Q_{GD} \\ \\ C_{iss} \\ C_{oss} \\ \\ C_{rss} \\ \end{array}$ $\begin{array}{l} t_{d(on)} \\ \\ t_{r} \\ \\ t_{d(off)} \\ \\ t_{f} \\ \\ \\ Source-d \\ \\ V_{SD} \\ \end{array}$	gate-drain charge input capacitance output capacitance reverse transfer capacitance turn-on delay time rise time turn-off delay time fall time rain diode	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 15}}{\text{Is}}$ $V_{DS} = 30 \text{ V}; R_L = 2 \Omega; V_{GS} = 5 \text{ V};$ $R_{G(ext)} = 10 \Omega$	- - - -	4.2 719 146 83 14.5 35 40 24	- 959 175 114 - - -	nC nC pF pF pF ns ns

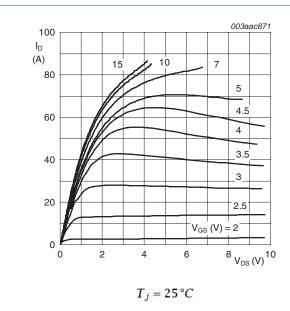


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values.

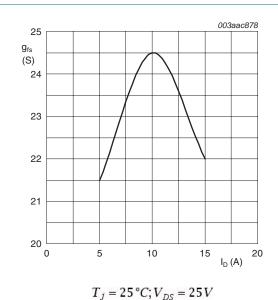


Fig 8. Forward transconductance as a function of drain current; typical values.

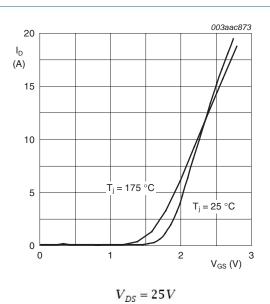


Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values.

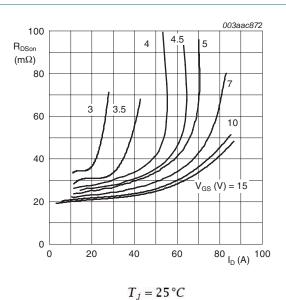


Fig 9. Drain-source on-state resistance as a function of drain current; typical values.

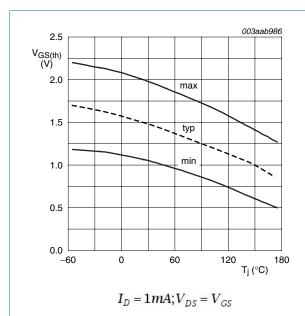


Fig 10. Gate-source threshold voltage as a function of junction temperature

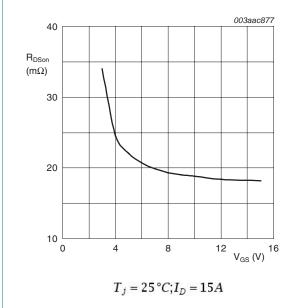
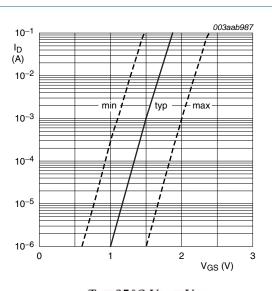


Fig 12. Drain-source on-state resistance as a function of gate-source voltage; typical values.



 $T_j = 25\,^{\circ}C; V_{DS} = V_{GS}$

Fig 11. Sub-threshold drain current as a function of gate-source voltage

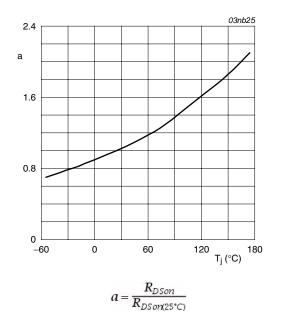


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

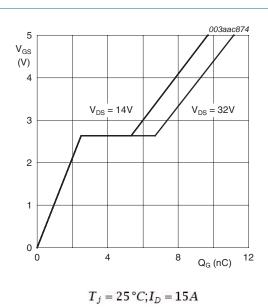
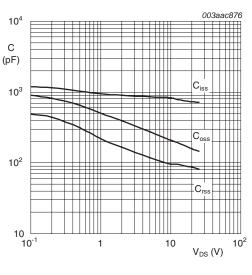
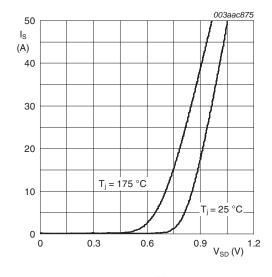


Fig 14. Gate-source voltage as a function of gate charge; typical values.



 $V_{GS} = 0V; f = 1MHz$

Fig 15. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.



 $V_{GS} = 0V$

Fig 16. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.

Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669

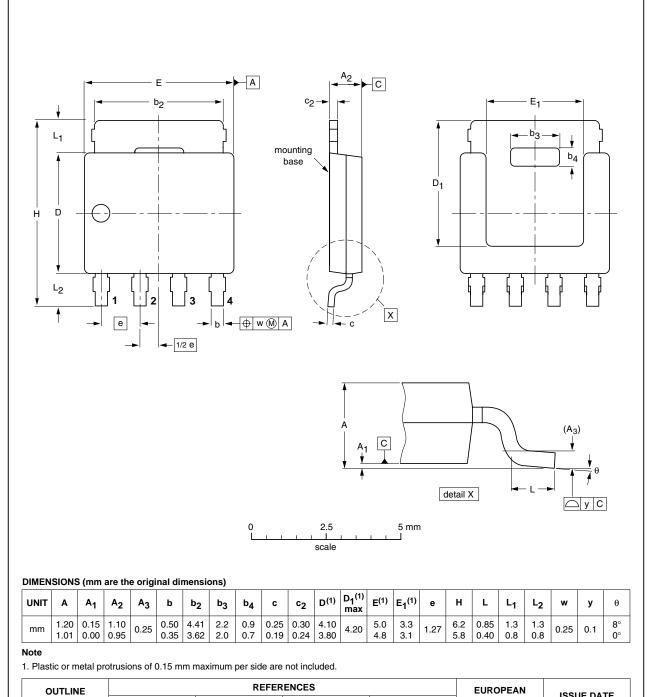


Fig 17. Package outline SOT669 (LFPAK)

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ISSUE DATE

04-10-13

06-03-16

PROJECTION

VERSION

SOT669



8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK9Y27-40B_4	20100407	Product data sheet	-	BUK9Y27-40B_3
Modifications:	 Status chair 	nged from objective to pro	oduct.	
BUK9Y27-40B_3	20100216	Objective data sheet	-	BUK9Y27-40B_2

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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BUK9Y27-40B

N-channel TrenchMOS logic level FET

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